

The International Conference on Silicon Carbide and Related Materials (ICSCRM2017)

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The conference I participated in, is the most important technical conference series in the world for electronics devices technology based on silicon carbide (SiC) and related materials. This year it was hold in Washington, D.C and that gave me the opportunity to meet more people and research works from US, who do not participate in conferences located in Europe.

At the conference I presented a poster entitled as : „SiC JBS Diode Symmetrical Voltage Doubler Represented as the Diffusion-Welded Stack“.



During the conference there were a lot of interesting research papers and presentations. The most exiting were

1. 4H-SiC 1200 V Junction Barrier Schottky Diodes with High Avalanche Ruggedness,

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2. Simultaneous Forward and Reverse Characterization of JBS Diodes Using Analytical Models for Outgoing Inspection
3. Study of Temperature-dependent Mechanisms and Characteristics of 4H-SiC Junction Barrier Schottky Rectifiers
etc.

In addition to the novel presentations, I had a chance to make negotiations with the presenters from Cree company and IOFFE Institute as well as with ITMO University concerning the epitaxial structures for silicon carbide, radiation defects in silicon carbide structures after electron and/or proton irradiation and discuss works for graphene sensors, which is the top topic for our future research area. The participation made it possible to gather all the needed people together and made a lot of talks.

During the poster presentations I had a large interest to our research work from Nitride Crystals company (USA), Wolfspeed Test Engineering Department (Wolfspeed is the world leader in silicon carbide—SiC—which outperforms silicon in every way), GE Global Research, Niskayuna, NY, USA etc.

Tallinn,

September 2017.

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